

规格书编号

**SPEC NO:** 

# 产品规格书 SPECIFICATION

CUSTOMER 客 户:							
PRODUCT 产品:	SAW RESONATOR						
MODEL NO 型 号:	HDR299M-F11						
PREPARED 编 制:	CHECKED 审 核	亥 <b>:</b>					
APPROVED 批准:	DATE 日 其	用: 2017-03-03					
客户确认 CUSTOMER RECEIVED:							
审核 CHECKED	批准 APPROVED	日期 DATE					

# 无锡市好达电子有限公司 Shoulder Electronics Limited



# 更改历史记录 History Record

更改日期 Date	规格书编号 Spec. No.	产品型号 Part No.	客户产品型号 Customer No.	更改内容描述 Modify Content	备注 Remark

# **SAW RESONATOR**

### 1. SCOPE

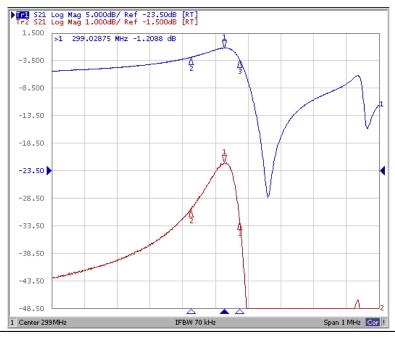
This specification shall cover the characteristics of 1-port SAW resonator with used for remote-control security.

# 2. ELECTRICAL SPECIFICATION

DC Voltage VDC	10V		
AC Voltage Vpp	10V50Hz/60Hz		
Operation temperature	-40°C to +85°C		
Storage temperature	-45°C to +85°C		
RF Power Dissipation	0dBm		

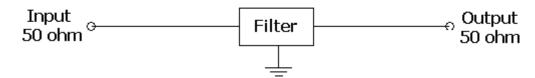
#### 2.2 Electronic Characteristics

Item		Unites	Minimum	Typical	Maximum
Center Frequency		MHz	298.925	299.000	299.075
Insertion Loss		dB		1.5	2.2
Quality Factor Unload Q			8000	12800	
50Ω Loaded Q			850	1500	
Temperature	Turnover Temperature	$^{\circ}\mathbb{C}$	10	25	40
Stability	Freq.temp.Coefficient	ppm/℃2		0.032	
Frequency Aging		ppm/yr		≤±10	
DC. Insulation Resistance		МΩ	1.0		
RF Equivalent RLC Model	Motional Resistance R1	Ω		21	
	I Motional Inductance I I	μН		174.83	
	Motional Capacitance C1	fF		1.6163	
Transducer Static Capacitance		pF		2.0	

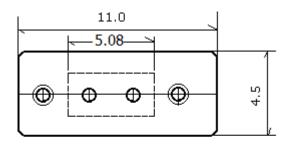


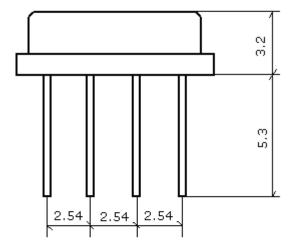


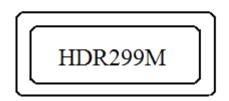
### 3. TEST CIRCUIT



#### 4. DIMENSION







# 5. ENVIRONMENTAL CHARACTERISTICS

#### 5-1 High temperature exposure

Subject the device to  $+85^{\circ}$ C for 16 hours. Then release the resonator into the room conditions for 24 hours prior to the measurement. It shall fulfill the specifications in 2.2.

#### 5-2 Low temperature exposure

Subject the device to  $-40^{\circ}$ C for 16 hours. Then release the device into the room conditions for 24 hours prior to the measurement. It shall fulfill the specifications in 2.2.

5-3 Temperature cycling



#### **SAW RESONATOR**

#### HDR299M-F11

Subject the device to a low temperature of  $-40^{\circ}$ C for 30 minutes. Following by a high temperature of  $+85^{\circ}$ C for 30 Minutes. Then release the device into the room conditions for 24 hours prior to the measurement. It shall meet the specifications in 2.2.

#### 5-4 Resistance to solder heat

Dip the device terminals no closer than 1.5mm into the solder bath at  $260^{\circ}\text{C} \pm 10^{\circ}\text{C}$  for  $10\pm 1$  sec. Then release the device into the room conditions for 4 hours. The device shall meet the specifications in 2.2.

#### 5-5 Solderability

Subject the device terminals into the solder bath at  $245^{\circ}\text{C} \pm 5^{\circ}\text{C}$  for 5s, More than 95% area of the terminals must be covered with new solder. It shall meet the specifications in 2.2.

#### 5-6 Mechanical shock

Drop the device randomly onto the concrete floor from the height of 1m 3 times. the device shall fulfill the specifications in 2.2.

#### 5-7 Vibration

Subject the device to the vibration for 1 hour each in x,y and z axes with the amplitude of 1.5 mm at 10 to 55 Hz. The device shall fulfill the specifications in 2.2.

#### 6. REMARK

#### 6.1 Static voltage

Static voltage between signal load & ground may cause deterioration &destruction of the component. Please avoid static voltage.

#### 6.2 Ultrasonic cleaning

Ultrasonic vibration may cause deterioration & destruction of the component. Please avoid ultrasonic cleaning

#### 6.3 Soldering

Only leads of component may be soldered. Please avoid soldering another part of component.